



November 2001

# FDD6512A/FDU6512A

## 20V N-Channel PowerTrench<sup>®</sup> MOSFET

### General Description

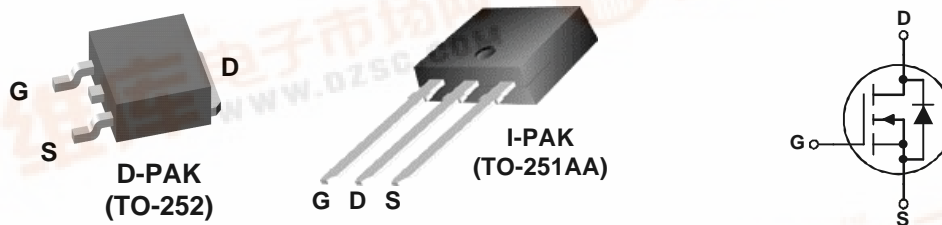
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $R_{DS(ON)}$ , fast switching speed and extremely low  $R_{DS(ON)}$  in a small package.

### Applications

- DC/DC converter
- Motor drives

### Features

- 36 A, 20 V  $R_{DS(ON)} = 21\text{ m}\Omega$  @  $V_{GS} = 4.5\text{ V}$   
 $R_{DS(ON)} = 31\text{ m}\Omega$  @  $V_{GS} = 2.5\text{ V}$
- Low gate charge (12 nC typical)
- Fast switching
- High performance trench technology for extremely low  $R_{DS(ON)}$



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Rated	Units
$V_{DSS}$	Drain-Source Voltage	20	V
$V_{GSS}$	Gate-Source Voltage	$\pm 12$	V
$I_D$	Continuous Drain Current @ $T_C=25^\circ\text{C}$ (Note 3)	36	A
	@ $T_A=25^\circ\text{C}$ (Note 1a)	10.7	
	Pulsed (Note 1a)	100	
$P_D$	Power Dissipation @ $T_C=25^\circ\text{C}$ (Note 3)	43	W
	@ $T_A=25^\circ\text{C}$ (Note 1a)	3.8	
	@ $T_A=25^\circ\text{C}$ (Note 1b)	1.6	
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +175	$^\circ\text{C}$

### Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)	3.5	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	40	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1b)	96	$^\circ\text{C/W}$

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape width	Quantity
FDD6512A	FDD6512A	D-PAK (TO-252)	13"	12mm	2500 units
FDU6512A	FDU6512A	I-PAK (TO-251)	Tube	N/A	75



## Electrical Characteristics

$T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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### Drain-Source Avalanche Ratings (Note 2)

$E_{AS}$	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 10\text{ V}$ , $I_D = 10\text{ A}$			90	mJ
$I_{AS}$	Drain-Source Avalanche Current				10	A

### Off Characteristics

$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}$ , $I_D = 250\ \mu\text{A}$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		14		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 16\text{ V}$ , $V_{GS} = 0\text{ V}$			10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage, Forward	$V_{GS} = 12\text{ V}$ , $V_{DS} = 0\text{ V}$			100	nA
$I_{GSSR}$	Gate-Body Leakage, Reverse	$V_{GS} = -12\text{ V}$ , $V_{DS} = 0\text{ V}$			-100	nA

### On Characteristics (Note 2)

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\ \mu\text{A}$	0.6	0.8	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		-3.2		mV/ $^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 4.5\text{ V}$ , $I_D = 10.7\text{ A}$ $V_{GS} = 2.5\text{ V}$ , $I_D = 9.1\text{ A}$ $V_{GS} = 4.5\text{ V}$ , $I_D = 10.7\text{ A}$ , $T_J = 125^\circ\text{C}$		16 21 22	21 31 29	m $\Omega$
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 4.5\text{ V}$ , $V_{DS} = 5\text{ V}$	50			A
$g_{FS}$	Forward Transconductance	$V_{DS} = 5\text{ V}$ , $I_D = 10.7\text{ A}$		50		S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 10\text{ V}$ , $V_{GS} = 0\text{ V}$ , $f = 1.0\text{ MHz}$		1082		pF
$C_{oss}$	Output Capacitance			277		pF
$C_{rss}$	Reverse Transfer Capacitance			130		pF

### Switching Characteristics (Note 2)

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 10\text{ V}$ , $I_D = 1\text{ A}$ , $V_{GS} = 4.5\text{ V}$ , $R_{GEN} = 6\ \Omega$		8	16	ns
$t_r$	Turn-On Rise Time			8	16	ns
$t_{d(off)}$	Turn-Off Delay Time			24	38	ns
$t_f$	Turn-Off Fall Time			8	16	ns
$Q_g$	Total Gate Charge		$V_{DS} = 10\text{ V}$ , $I_D = 10.7\text{ A}$ , $V_{GS} = 4.5\text{ V}$		12	19
$Q_{gs}$	Gate-Source Charge			2		nC
$Q_{gd}$	Gate-Drain Charge			3		nC

### Drain-Source Diode Characteristics and Maximum Ratings

$I_S$	Maximum Continuous Drain-Source Diode Forward Current			2.3	A	
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}$ , $I_S = 2.3\text{ A}$ (Note 2)		0.72	1.2	V

#### Notes:

1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a)  $R_{\theta JA} = 40^\circ\text{C/W}$  when mounted on a  $1\text{ in}^2$  pad of 2 oz copper



b)  $R_{\theta JA} = 96^\circ\text{C/W}$  when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 $\mu\text{s}$ , Duty Cycle < 2.0%

3. Maximum current is calculated as: 
$$I_{D(max)} = \sqrt{\frac{P_D}{R_{DS(on)}}}$$

where  $P_D$  is maximum power dissipation at  $T_C = 25^\circ\text{C}$  and  $R_{DS(on)}$  is at  $T_{J(max)}$  and  $V_{GS} = 10\text{ V}$ . Package current limitation is 21A

## Typical Characteristics

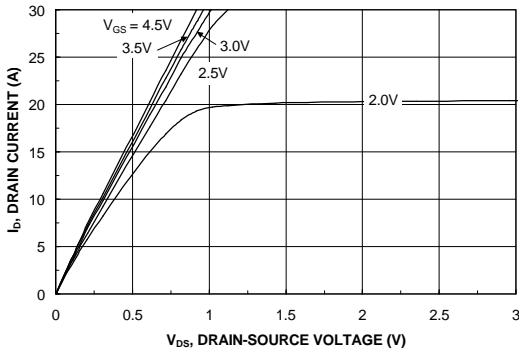


Figure 1. On-Region Characteristics

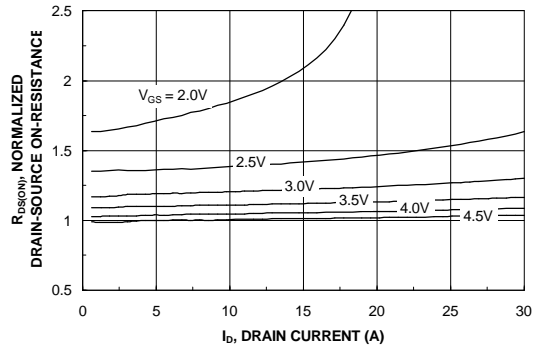


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

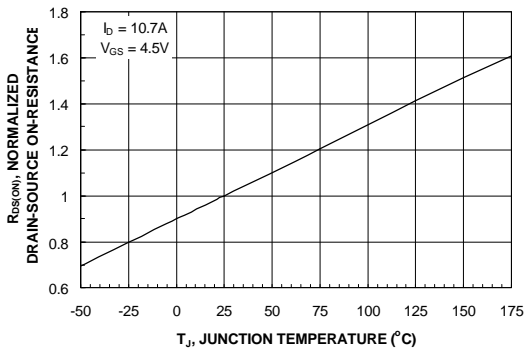


Figure 3. On-Resistance Variation with Temperature

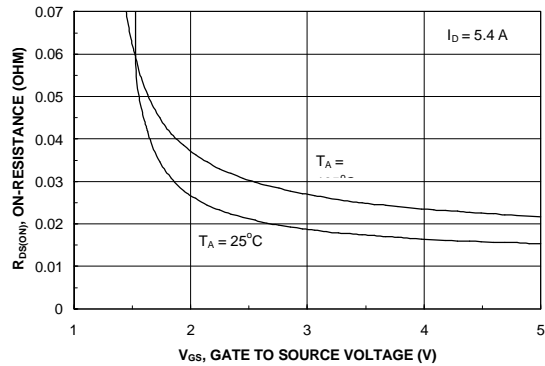


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

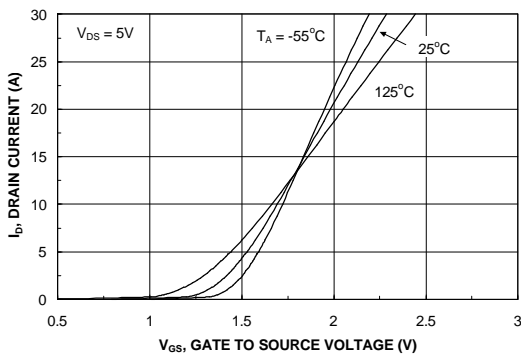


Figure 5. Transfer Characteristics

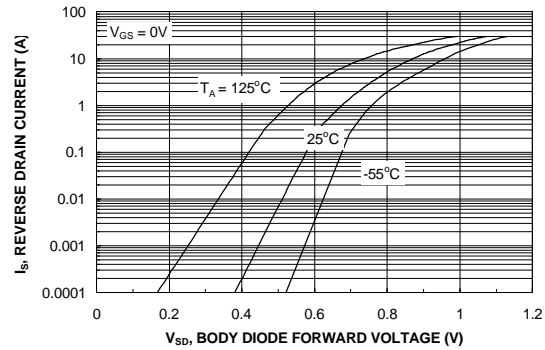
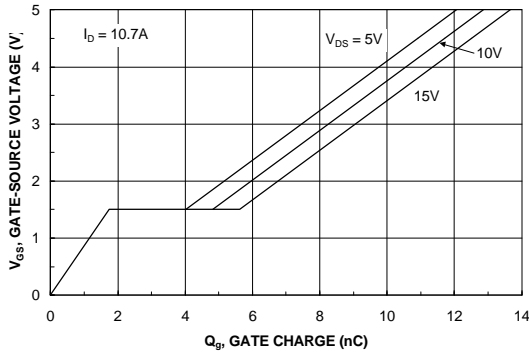
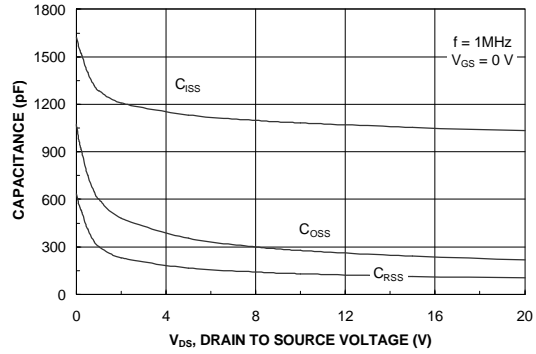


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

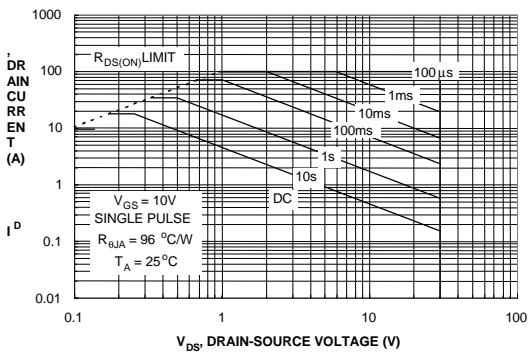
## Typical Characteristics



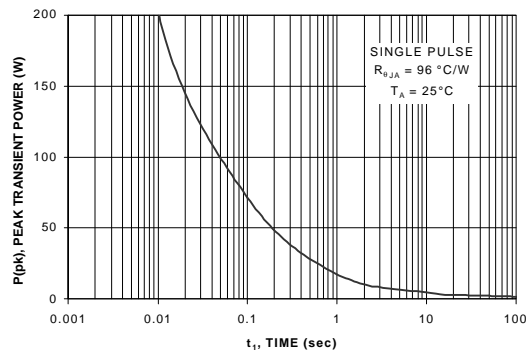
**Figure 7. Gate Charge Characteristics**



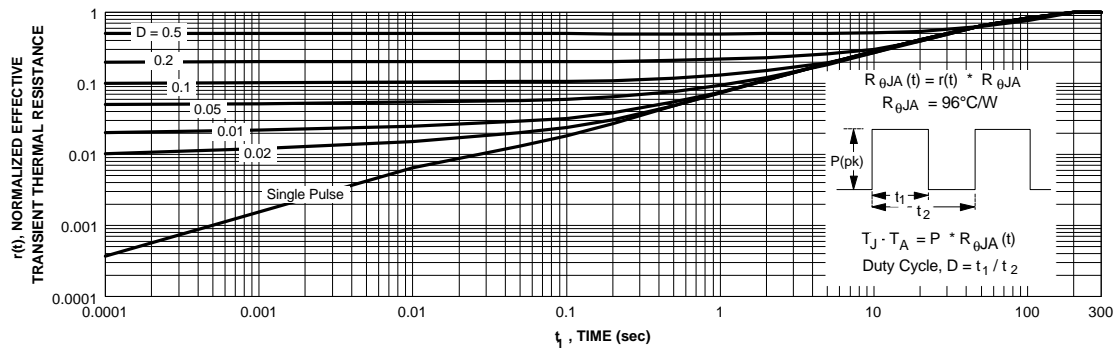
**Figure 8. Capacitance Characteristics**



**Figure 9. Maximum Safe Operating Area**



**Figure 10. Single Pulse Maximum Power Dissipation**



**Figure 11. Transient Thermal Response Curve**

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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